

Q: How do you customize the AutoTest logfile format?

Customizing The AutoTest Log File

Data logging of AutoTest results can be customized to help meet a user's desired format. To enable this feature, first you must activate the keyword *CustomAutoTestLogTemplate* in file *SpScript.txt* by removing the leading semicolon from the line containing this keyword (or by typing in the keyword on a blank line if it is not already present). The file *SpScript.txt* is located in *c:\Symphony*. The keyword must be followed by the name of the file that contains log file format. Here is an example of this *SpScript.txt* line:

```
CustomAutoTestLogTemplate c:\Symphony\ATTempl.txt
```

In this example, "ATTempl.txt" is the template file that the feature is using for parameters. An example of the contents of *ATTempl.txt* appears in this document. If the file is not present, then standard data logging will be used. The Custom Log File feature can be used only in the "single site mode" at this time.

Once the *SpScript.txt* file has been edited to enable the feature, save it and restart the Symphony software (you must close Symphony software if it is already running). This will automatically enable the feature.

The Log File Format appears below in its basic form:

```
#section_name  
<field_name>  
.  
.  
#end
```

The following section names are available:

```
#DEFINE - defines PASS and FAIL character strings  
#HEADER - this section contains strings that will appear in the log file header  
#DETAILS - this section contains the string that will be saved in the log file for every  
executed test
```

Each section can contain special keywords (always in brackets < > - except for the DEFINE section), which will add information to the log file. Keywords that cannot be recognized will be ignored. Strings that are not in brackets will simply be copied into the log file.

The following keywords are allowed for the specified sections:

#DEFINE section

(If there are no defined strings – default strings will be used (“Passed” and “Failed”))

Passed - string used to indicate “passed” test
Failed - string used to indicate “failed” test

#HEADER section

<DATE> - current date
<TIME> - current time
<SERNR> - serial number (from More Info window)
<OPERATOR> - operator name (from More Info window)
<ENVIRONMENT > - environment (from More Info window)
<NOTES> - notes (from More Info window)
<DEVICENAME> - device name
<DEVICENR> - device number
<LOTID> - lot ID
<WAFERID> - wafer ID
<XYPOS> - die position

#DETAILS section

<TESTNR> - test number
<TESTNAME> - test name
<LOWLIMIT> - low limit
<HIGHLIMIT> - high limit
<RESULT> - test result
<PASSFAIL> - “passed”/”failed” string

A basic example of a template file (ATTempl.txt) appears on the next page.

```

#DEFINE
Passed p
Failed f
#END

#HEADER
Auto Test Log File '<DEVICENAME>'
Date <DATE> <TIME>
Operator <OPERATOR>
Environment <ENVIRONMENT>
Device # <DEVICENR>
Serial Number <SERNR>
#END

#DETAILS
Test <TESTNR>, <TESTNAME>, <LOWLIMIT>, <HIGHLIMIT>, <RESULT>, <PF>
#END

```

Basic example of template file "ATTempl.txt"

The string to the left of the bracketed keyword is the label defined by the user that will appear in the AutoTest log file, and it will be followed by data entered at the time of test execution (represented by the keyword). Only one line appears for each test. However, if there is a failure, the first failed pin only appears on the line; other failed pins must be identified by standard logging or by Failure Analysis. The Auto Test Log file for the above example will then look like the example below.

```

Auto Test Log File 'PostBake'
Date 7/12/2004 5:35:03 PM
Operator Peter
Environment HOT
Device # 1
Serial Number 0098

Test 2,SupplyCurr, 1.000 mA, 250.000 mA,0.000 nA,p
Test 3,RecXmit, , , ,p
Test 4,Den, , , ,p
Test 6,PROMA, , , ,p
Test 7,PROMB, , , ,p
Test 10,IILStd, -500.000 uA, , 0.000 nA,p
Test 11,IIL0v, , 10.000 uA, 0.000 nA,p
Test 12,IILGac, -300.000 uA, -20.000 uA, 0.000 nA,f
Test 13,IILdiff, -20.000 uA, 20.000 uA, 0.000 nA,p
Test 14,IILHstd, -300.000 uA, 10.000 uA, 0.000 nA,p
Test 15,IILHOv, 40.000 uA, 400.000 uA, 0.000 nA,f
Test 16,IILHdiff, 50.000 uA, 220.000 uA, 0.000 nA,f
Test 17,VOLp, 0.350 V, 1.400 V, 0.000 nV,f
Test 18,VOHp, 4.100 V, 5.040 V, 0.000 nV,f
Test 19,VOHen, 4.800 V, 5.500 V, 0.000 nV,f
Test 21,DynCurr, -1.000 mA, 150.000 mA,0.000 nA,p
Test 26,GDel, 30.0ns, 100.0ns,82.5ns,p

$$$$$$$$ SUMMARY REPORT $$$$$$$$

Total Devices: 1; Passed: 0; Failed: 1; Yield = 0%

```

Custom AutoTest Logfile with "More Information"

Also see Q'nApp #S47 on the "More..." button.